Notice of References Cited Application/Control No. 10/711,772 Examiner /BINH K. TIEU/ Applicant(s)/Patent Under Reexamination CHARYTAN ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Ā	US-2005/0116028	06-2005	Cohen et al.	235/380
*	В	US-2004/0139318	07-2004	Fiala et al.	713/165
*	С	US-7,290,703	11-2007	Jacobs, David A.	235/380
* .	D	US-2005/0008132	01-2005	Paschini et al.	379/093.12
*	E	US-2004/0120475	06-2004	Bauer et al.	379/088.18
*	F	US-2002/0088851	07-2002	Hodes, Mark B.	235/380
*	G	US-2005/0123112	06-2005	New et al.	379/114.2
	Н	US-			
	ı	US-			
	J	US-			
	K	US-		,	
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					•
	Р					
	Q					
	R			·	•	
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.